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### What is "[Embedded - Microcontrollers](#)"?

"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

### Applications of "[Embedded - Microcontrollers](#)"

#### Details

Product Status	Active
Core Processor	ARM® Cortex®-M4
Core Size	32-Bit Single-Core
Speed	120MHz
Connectivity	CANbus, I <sup>2</sup> C, LINbus, SPI, UART/USART, USB
Peripherals	DMA, I <sup>2</sup> S, LED, POR, PWM, WDT
Number of I/O	55
Program Memory Size	256KB (256K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	80K x 8
Voltage - Supply (Vcc/Vdd)	3.13V ~ 3.63V
Data Converters	A/D 24x12b; D/A 2x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 125°C (TA)
Mounting Type	Surface Mount
Package / Case	100-LQFP Exposed Pad
Supplier Device Package	PG-LQFP-100-25
Purchase URL	<a href="https://www.e-xfl.com/product-detail/infineon-technologies/xmc4402f100k256baxqma1">https://www.e-xfl.com/product-detail/infineon-technologies/xmc4402f100k256baxqma1</a>

## XMC4400 Data Sheet

### Revision History: V1.2 2015-12

Previous Versions:

V1.1 2014-03

V1.0 2013-10

V0.6 2012-11

Page	Subjects
<b>12</b>	Added a section listing the packages of the different markings.
<b>14</b>	Added BA marking variant.
<b>37</b>	Added footnote explaining minimum $V_{BAT}$ requirements to start the hibernate domain and/or oscillation of a crystal on RTC_XTAL.
<b>38</b>	Changed pull device definition to System Requirement (SR) to reflect that the specified currents are defined by the characteristics of the external load/driver.
<b>38</b>	Added information that $\overline{PORST}$ Pull-up is identical to the pull-up on standard I/O pins.
<b>45</b>	Updated $C_{AINSW}$ , $C_{AINTOT}$ and $R_{AIN}$ parameters with improved values.
<b>59</b>	Added footnote on test configuration for LPAC measurement.
<b>61</b>	Corrected parameter name of of USB pull device (upstream port receiving) definition according to USB standard (referenced to DM instead of DP)
<b>66</b>	Relaxed RTC_XTAL $V_{PPX}$ parameter value and changed it to a system requirement.
<b>70</b>	Added footnote on current consumption by enabling of $f_{CCU}$ .
<b>71</b>	Added Flash endurance parameter for 64 Kbytes Physical Sector PS4 $N_{EPS4}$ for devices with BA marking.
many	Added PG-TQFP-64-19 and PG-LQFP-100-25 package information.
<b>97, 100</b>	Added tables describing the differences between PG-LQFP-100-11 to PG-LQFP-100-25 as well as PG-LQFP-64-19 to PG-TQFP-64-19 packages.
<b>102</b>	Updated to JEDEC standard J-STD-020D for the moisture sensitivity level and added solder temperature parameter according to the same standard.

### Trademarks

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**On-Chip Memories**

- 16 KB on-chip boot ROM
- 16 KB on-chip high-speed program memory
- 32 KB on-chip high speed data memory
- 32 KB on-chip high-speed communication memory
- 512 KB on-chip Flash Memory with 4 KB instruction cache

**Communication Peripherals**

- Ethernet MAC module capable of 10/100 Mbit/s transfer rates
- Universal Serial Bus, USB 2.0 host, Full-Speed OTG, with integrated PHY
- Controller Area Network interface (MultiCAN), Full-CAN/Basic-CAN with two nodes, 64 message objects (MO), data rate up to 1MBit/s
- Four Universal Serial Interface Channels (USIC), providing four serial channels, usable as UART, double-SPI, quad-SPI, IIC, IIS and LIN interfaces
- LED and Touch-Sense Controller (LEDTS) for Human-Machine interface

**Analog Frontend Peripherals**

- Four Analog-Digital Converters (VADC) of 12-bit resolution, 8 channels each, with input out-of-range comparators
- Delta Sigma Demodulator with four channels, digital input stage for A/D signal conversion
- Digital-Analog Converter (DAC) with two channels of 12-bit resolution

**Industrial Control Peripherals**

- Two Capture/Compare Units 8 (CCU8) for motor control and power conversion
- Four Capture/Compare Units 4 (CCU4) for use as general purpose timers
- Four High Resolution PWM (HRPWM) channels
- Two Position Interfaces (POSIF) for servo motor positioning
- Window Watchdog Timer (WDT) for safety sensitive applications
- Die Temperature Sensor (DTS)
- Real Time Clock module with alarm support
- System Control Unit (SCU) for system configuration and control

**Input/Output Lines**

- Programmable port driver control module (PORTS)
- Individual bit addressability
- Tri-stated in input mode
- Push/pull or open drain output mode
- Boundary scan test support over JTAG interface

## On-Chip Debug Support

- Full support for debug features: 8 breakpoints, CoreSight, trace
- Various interfaces: ARM-JTAG, SWD, single wire trace

## 1.1 Ordering Information

The ordering code for an Infineon microcontroller provides an exact reference to a specific product. The code "XMC4<DDD>-<Z><PPP><T><FFFF>" identifies:

- <DDD> the derivatives function set
- <Z> the package variant
  - E: LFBGA
  - F: LQFP
  - Q: VQFN
- <PPP> package pin count
- <T> the temperature range:
  - F: -40°C to 85°C
  - K: -40°C to 125°C
- <FFFF> the Flash memory size.

For ordering codes for the XMC4400 please contact your sales representative or local distributor.

This document describes several derivatives of the XMC4400 series, some descriptions may not apply to a specific product. Please see [Table 1](#).

For simplicity the term **XMC4400** is used for all derivatives throughout this document.

## 1.2 Device Types

These device types are available and can be ordered through Infineon's direct and/or distribution channels.

**Table 1 Synopsis of XMC4400 Device Types**

Derivative <sup>1)</sup>	Package	Flash Kbytes	SRAM Kbytes
XMC4400-F100x512	PG-LQFP-100	512	80
XMC4400-F64x512	PG-yQFP-64 <sup>2)</sup>	512	80
XMC4400-F100x256	PG-LQFP-100	256	80
XMC4400-F64x256	PG-yQFP-64 <sup>2)</sup>	256	80
XMC4402-F100x256	PG-LQFP-100	256	80
XMC4402-F64x256	PG-yQFP-64 <sup>2)</sup>	256	80

1) x is a placeholder for the supported temperature range.

2) y is a placeholder for the QFP package variant, LQFP or TQFP depending on the stepping, see [Section 1.3](#).

### 1.3 Package Variants

Different markings of the XMC4400 use different package variants. Details of those packages are given in the [Package Parameters](#) section of the Data Sheet.

**Table 2 XMC4400 Package Variants**

Package Variant	Marking	Package
XMC4400-F100	EES-AA, ES-AA, ES-AB, AB	PG-LQFP-100-11
XMC4400-F64		PG-LQFP-64-19
XMC4400-F100	BA	PG-LQFP-100-25
XMC4400-F64		PG-TQFP-64-19

### 1.4 Device Type Features

The following table lists the available features per device type.

**Table 3 Features of XMC4400 Device Types**

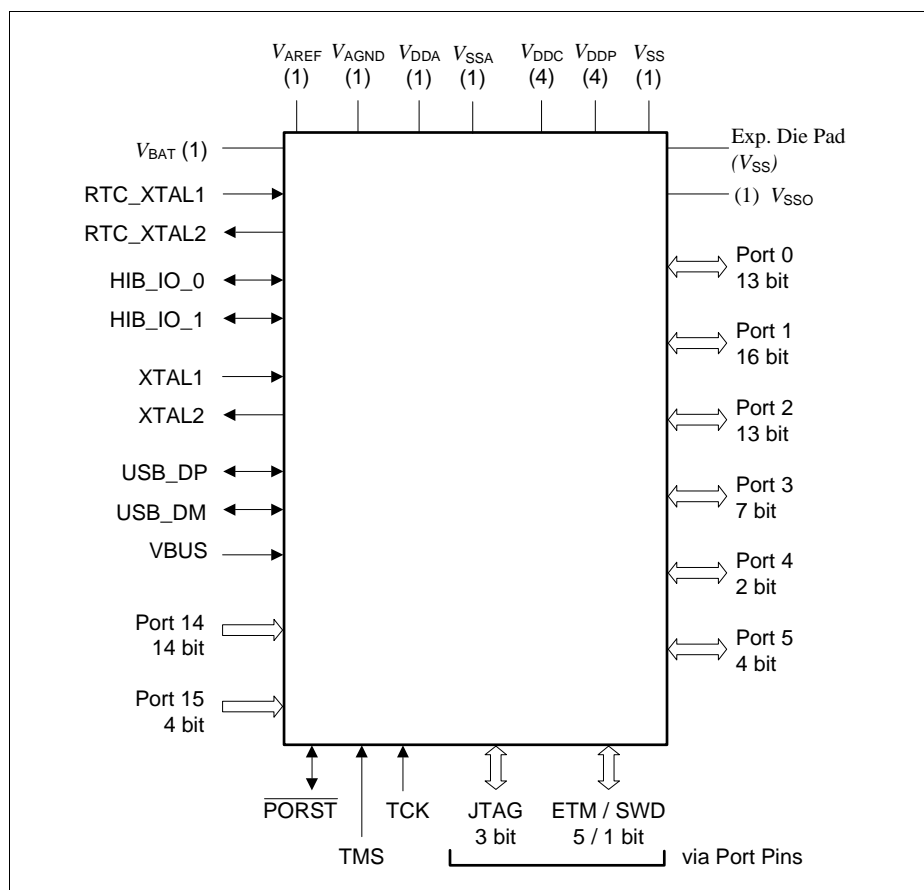
Derivative <sup>1)</sup>	LEDTS Intf.	ETH Intf.	USB Intf.	USIC Chan.	MultiCAN Nodes, MO
XMC4400-F100x512	1	RMII	1	2 x 2	N0, N1 MO[0..63]
XMC4400-F64x512	1	RMII	1	2 x 2	N0, N1 MO[0..63]
XMC4400-F100x256	1	RMII	1	2 x 2	N0, N1 MO[0..63]
XMC4400-F64x256	1	RMII	1	2 x 2	N0, N1 MO[0..63]
XMC4402-F100x256	1	—	1	2 x 2	N0, N1 MO[0..63]
XMC4402-F64x256	1	—	1	2 x 2	N0, N1 MO[0..63]

1) x is a placeholder for the supported temperature range.

## 2 General Device Information

This section summarizes the logic symbols and package pin configurations with a detailed list of the functional I/O mapping.

### 2.1 Logic Symbols



**Figure 2 XMC4400 Logic Symbol PG-LQFP-100**

## 2.2.1 Package Pin Summary

The following general scheme is used to describe each pin:

**Table 9 Package Pin Mapping Description**

Function	Package A	Package B	...	Pad Type	Notes
Name	N	Ax	...	A2	

The table is sorted by the “Function” column, starting with the regular Port pins (Px.y), followed by the dedicated pins (i.e. PORST) and supply pins.

The following columns, titled with the supported package variants, lists the package pin number to which the respective function is mapped in that package.

The “Pad Type” indicates the employed pad type (A1, A1+, A2, special=special pad, In=input pad, AN/DIG\_IN=analog and digital input, Power=power supply). Details about the pad properties are defined in the Electrical Parameters.

In the “Notes”, special information to the respective pin/function is given, i.e. deviations from the default configuration after reset. Per default the regular Port pins are configured as direct input with no internal pull device active.

**Table 10 Package Pin Mapping**

Function	LQFP-100	LQFP-64 TQFP-64	Pad Type	Notes
P0.0	2	2	A1+	
P0.1	1	1	A1+	
P0.2	100	64	A2	
P0.3	99	63	A2	
P0.4	98	62	A2	
P0.5	97	61	A2	
P0.6	96	60	A2	
P0.7	89	58	A2	After a system reset, via HWSEL this pin selects the DB.TDI function.
P0.8	88	57	A2	After a system reset, via HWSEL this pin selects the DB.TRST function, with a weak pull-down active.
P0.9	4	4	A2	
P0.10	3	3	A1+	

**General Device Information**
**Table 10 Package Pin Mapping (cont'd)**

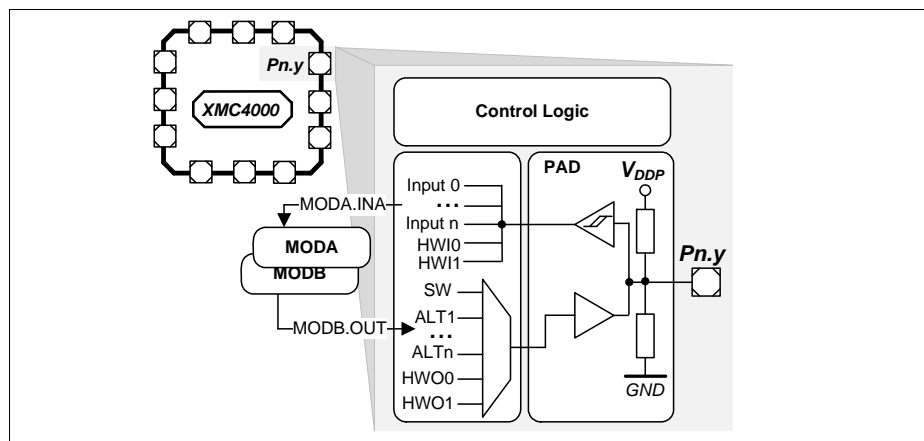
Function	LQFP-100	LQFP-64 TQFP-64	Pad Type	Notes
USB_DP	9	6	special	
USB_DM	8	5	special	
HIB_IO_0	14	10	A1 special	At the first power-up and with every reset of the hibernate domain this pin is configured as open-drain output and drives "0". As output the medium driver mode is active.
HIB_IO_1	13	-	A1 special	At the first power-up and with every reset of the hibernate domain this pin is configured as input with no pull device active. As output the medium driver mode is active.
TCK	67	45	A1	Weak pull-down active.
TMS	66	44	A1+	Weak pull-up active. As output the strong-soft driver mode is active.
PORST	65	43	special	Strong pull-down controlled by EVR. Weak pull-up active while strong pull-down is not active.
XTAL1	61	39	clock_IN	
XTAL2	62	40	clock_O	
RTC_XTAL1	15	11	clock_IN	
RTC_XTAL2	16	12	clock_O	
VBAT	17	13	Power	When VDDP is supplied VBAT has to be supplied as well.
VBUS	10	7	special	
VAREF	33	-	AN_Ref	
VAGND	32	-	AN_Ref	
VDDA	35	-	AN_Power	

## 2.2.2 Port I/O Functions

The following general scheme is used to describe each PORT pin:

**Table 11 Port I/O Function Description**

Function	Outputs			Inputs		
	ALT1	ALTn	HWO0	HWI0	Input	Input
P0.0		MODA.OUT	MODB.OUT	MODB.INA	MODC.INA	
Pn.y	MODA.OUT				MODA.INA	MODC.INB



**Figure 6 Simplified Port Structure**

Pn.y is the port pin name, defining the control and data bits/registers associated with it. As GPIO, the port is under software control. Its input value is read via Pn\_IN.y, Pn\_OUT defines the output value.

Up to four alternate output functions (ALT1/2/3/4) can be mapped to a single port pin, selected by Pn\_IOC.R.PC. The output value is directly driven by the respective module, with the pin characteristics controlled by the port registers (within the limits of the connected pad).

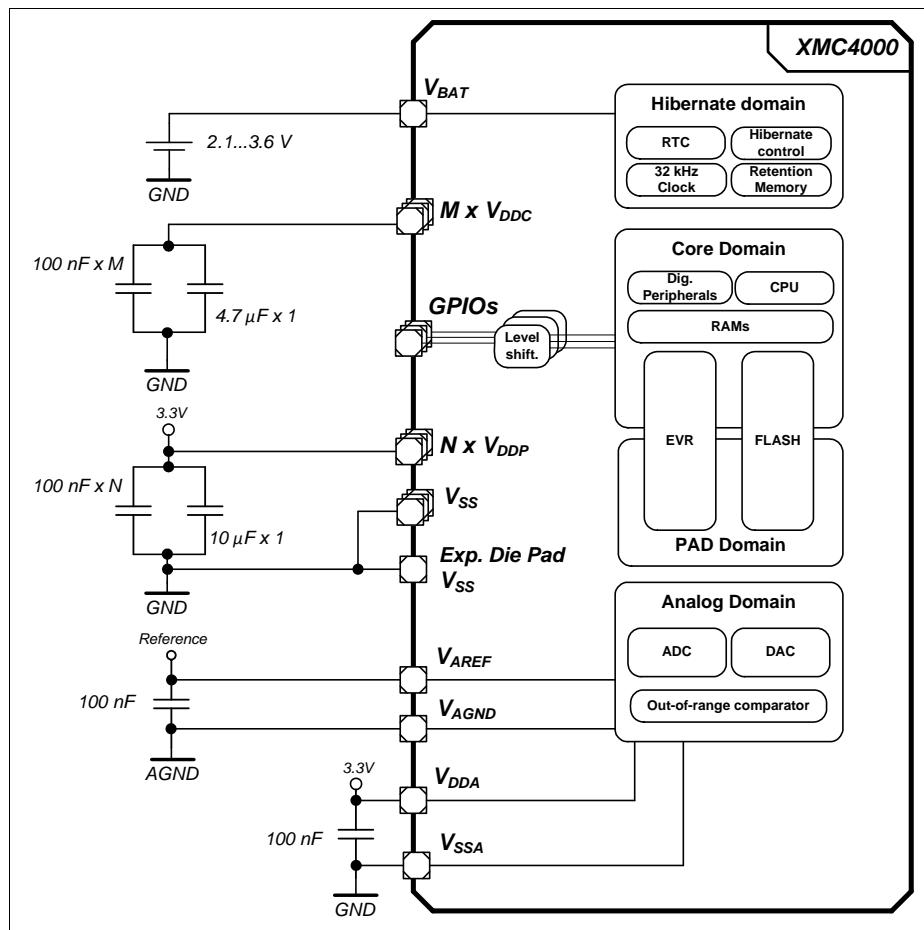
The port pin input can be connected to multiple peripherals. Most peripherals have an input multiplexer to select between different possible input sources.

The input path is also active while the pin is configured as output. This allows to feedback an output to on-chip resources without wasting an additional external pin.

By Pn\_HWSEL it is possible to select between different hardware “masters” (HWO0/HWI0). The selected peripheral can take control of the pin(s). Hardware control overrules settings in the respective port pin registers.

## 2.3 Power Connection Scheme

**Figure 7.** shows a reference power connection scheme for the XMC4400.



**Figure 7 Power Connection Scheme**

Every power supply pin needs to be connected. Different pins of the same supply need also to be externally connected. As example, all  $V_{DDP}$  pins must be connected externally to one  $V_{DDP}$  net. In this reference scheme one 100 nF capacitor is connected at each supply pin against  $V_{SS}$ . An additional 10  $\mu$ F capacitor is connected to the  $V_{DDP}$  nets and an additional 4.7  $\mu$ F capacitor to the  $V_{DDC}$  nets.

## **3 Electrical Parameters**

### **3.1 General Parameters**

#### **3.1.1 Parameter Interpretation**

The parameters listed in this section partly represent the characteristics of the XMC4400 and partly its requirements on the system. To aid interpreting the parameters easily when evaluating them for a design, they are marked with an two-letter abbreviation in column "Symbol":

- **CC**  
Such parameters indicate **C**ontroller **C**haracteristics, which are a distinctive feature of the XMC4400 and must be regarded for system design.
- **SR**  
Such parameters indicate **S**ystem **R**equirements, which must be provided by the application system in which the XMC4400 is designed in.

### 3.1.2 Absolute Maximum Ratings

Stresses above the values listed under “Absolute Maximum Ratings” may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions may affect device reliability.

**Table 13 Absolute Maximum Rating Parameters**

Parameter	Symbol		Values			Unit	Note / Test Condition
			Min.	Typ.	Max.		
Storage temperature	$T_{ST}$	SR	-65	–	150	°C	–
Junction temperature	$T_J$	SR	-40	–	150	°C	–
Voltage at 3.3 V power supply pins with respect to $V_{SS}$	$V_{DDP}$	SR	–	–	4.3	V	–
Voltage on any Class A and dedicated input pin with respect to $V_{SS}$	$V_{IN}$	SR	-1.0	–	$V_{DDP} + 1.0$ or max. 4.3	V	whichever is lower
Voltage on any analog input pin with respect to $V_{AGND}$	$V_{AIN}$ $V_{AREF}$	SR	-1.0	–	$V_{DDP} + 1.0$ or max. 4.3	V	whichever is lower
Input current on any pin during overload condition	$I_{IN}$	SR	-10	–	+10	mA	
Absolute maximum sum of all input circuit currents for one port group during overload condition <sup>1)</sup>	$\Sigma I_{IN}$	SR	-25	–	+25	mA	
Absolute maximum sum of all input circuit currents during overload condition	$\Sigma I_{IN}$	SR	-100	–	+100	mA	

1) The port groups are defined in [Table 17](#).

**Electrical Parameters**
**Table 22 Standard Pads Class\_A1+**

Parameter	Symbol	Values		Unit	Note / Test Condition
		Min.	Max.		
Output high voltage, POD <sup>1)</sup> = weak	V <sub>OHA1+</sub> CC	V <sub>DDP</sub> - 0.4	–	V	I <sub>OH</sub> ≥ -400 μA
		2.4	–	V	I <sub>OH</sub> ≥ -500 μA
Output high voltage, POD <sup>1)</sup> = medium		V <sub>DDP</sub> - 0.4	–	V	I <sub>OH</sub> ≥ -1.4 mA
		2.4	–	V	I <sub>OH</sub> ≥ -2 mA
Output high voltage, POD <sup>1)</sup> = strong		V <sub>DDP</sub> - 0.4	–	V	I <sub>OH</sub> ≥ -1.4 mA
		2.4	–	V	I <sub>OH</sub> ≥ -2 mA
Output low voltage	V <sub>OLA1+</sub> CC	–	0.4	V	I <sub>OL</sub> ≤ 500 μA; POD <sup>1)</sup> = weak
		–	0.4	V	I <sub>OL</sub> ≤ 2 mA; POD <sup>1)</sup> = medium
		–	0.4	V	I <sub>OL</sub> ≤ 2 mA; POD <sup>1)</sup> = strong
Fall time	t <sub>FA1+</sub> CC	–	150	ns	C <sub>L</sub> = 20 pF; POD <sup>1)</sup> = weak
		–	50	ns	C <sub>L</sub> = 50 pF; POD <sup>1)</sup> = medium
		–	28	ns	C <sub>L</sub> = 50 pF; POD <sup>1)</sup> = strong; edge = slow
		–	16	ns	C <sub>L</sub> = 50 pF; POD <sup>1)</sup> = strong; edge = soft;
Rise time	t <sub>RA1+</sub> CC	–	150	ns	C <sub>L</sub> = 20 pF; POD <sup>1)</sup> = weak
		–	50	ns	C <sub>L</sub> = 50 pF; POD <sup>1)</sup> = medium
		–	28	ns	C <sub>L</sub> = 50 pF; POD <sup>1)</sup> = strong; edge = slow
		–	16	ns	C <sub>L</sub> = 50 pF; POD <sup>1)</sup> = strong; edge = soft

1) POD = Pin Out Driver

### 3.2.10 Power Supply Current

The total power supply current defined below consists of a leakage and a switching component.

Application relevant values are typically lower than those given in the following tables, and depend on the customer's system operating conditions (e.g. thermal connection or used application configurations).

*Note: These parameters are not subject to production test, but verified by design and/or characterization.*

If not stated otherwise, the operating conditions for the parameters in the following table are:

$$V_{DDP} = 3.3 \text{ V}, T_A = 25 \text{ }^{\circ}\text{C}$$

**Table 39 Power Supply Parameters**

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Active supply current <sup>1)</sup> Peripherals enabled Frequency: $f_{CPU}/f_{PERIPH}/f_{CCU}$ in MHz	$I_{DDPA}$ CC	–	113	–	mA	120 / 120 / 120
		–	102	–		120 / 60 / 60
		–	82	–		60 / 60 / 120
		–	61	–		24 / 24 / 24
		–	51	–		1 / 1 / 1
Active supply current Code execution from RAM Flash in Sleep mode Frequency: $f_{CPU}/f_{PERIPH}/f_{CCU}$ in MHz	$I_{DDPA}$ CC	–	53	–	mA	120 / 120 / 120
		–	50	–		120 / 60 / 60
Active supply current <sup>2)</sup> Peripherals disabled Frequency: $f_{CPU}/f_{PERIPH}$ in MHz	$I_{DDPA}$ CC	–	80	–	mA	120 / 120 / 120
		–	80	–		120 / 60 / 60
		–	65	–		60 / 60 / 120
		–	55	–		24 / 24 / 24
		–	50	–		1 / 1 / 1

**Electrical Parameters**
**Table 39 Power Supply Parameters**

Parameter	Symbol		Values			Unit	Note / Test Condition
			Min.	Typ.	Max.		
Power Dissipation	$P_{DISS}$	CC	—	—	1	W	$V_{DDP} = 3.6 \text{ V}$ , $T_J = 150 \text{ }^{\circ}\text{C}$
Wake-up time from Sleep to Active mode	$t_{SSA}$	CC	—	6	—	cycles	
Wake-up time from Deep Sleep to Active mode			—	—	—	ms	Defined by the wake-up of the Flash module, see <a href="#">Section 3.2.11</a>
Wake-up time from Hibernate mode			—	—	—	ms	Wake-up via power-on reset event, see <a href="#">Section 3.3.2</a>

- 1) CPU executing code from Flash, all peripherals idle.
- 2) CPU executing code from Flash. Ethernet, USB and CCU clock off.
- 3) CPU in sleep, all peripherals idle, Flash in Active mode.
- 4) CPU in sleep, Flash in Active mode.
- 5) CPU in sleep, peripherals disabled, after wake-up code execution from RAM.
- 6) To wake-up the Flash from its Sleep mode,  $f_{CPU} \geq 1 \text{ MHz}$  is required.
- 7) OSC\_ULP operating with external crystal on RTC\_XTAL
- 8) OSC\_ULP off, Hibernate domain operating with OSC\_SI clock
- 9) Test Power Loop:  $f_{SYS} = 120 \text{ MHz}$ , CPU executing benchmark code from Flash, all CCUs in 100kHz timer mode, all ADC groups in continuous conversion mode, USICs as SPI in internal loop-back mode, CAN in 500kHz internal loop-back mode, interrupt triggered DMA block transfers to parity protected RAMs and FCE, DTS measurements and FPU calculations.  
The power consumption of each customer application will most probably be lower than this value, but must be evaluated separately.
- 10)  $I_{DDP}$  decreases typically by 5 mA when  $f_{SYS}$  decreases by 10 MHz, at constant  $T_J$
- 11) Sum of currents of all active converters (ADC and DAC)

**Peripheral Idle Currents**

Test conditions:

- $f_{\text{sys}}$  and derived clocks at 120 MHz
- $V_{\text{DDP}} = 3.3 \text{ V}$ ,  $T_a = 25^\circ\text{C}$
- all peripherals are held in reset (see the PRSTAT registers in the Reset Control Unit of the SCU)
- the peripheral clocks are disabled (see CGATSTAT registers in the Clock Control Unit of the SCU)
- no I/O activity
- the given values are a result of differential measurements with asserted and deasserted peripheral reset and enabled clock of the peripheral under test

The tested peripheral is left in the state after the peripheral reset is deasserted, no further initialisation or configuration is done. E.g. no timer is running in the CCUs, no communication active in the USICs, etc.

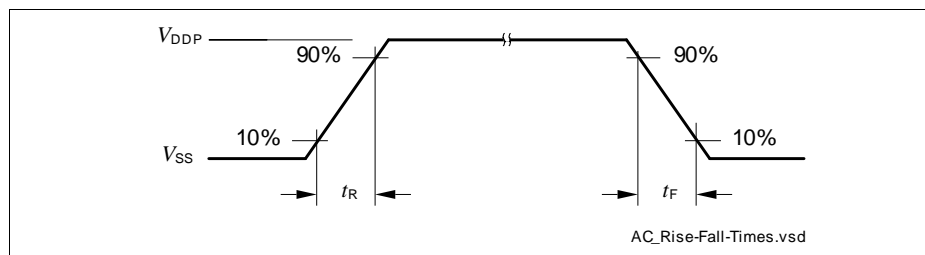
**Table 40 Peripheral Idle Currents**

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
PORTS ETH USB FCE WDT POSIFx	$I_{\text{PER CC}}$	–	$\leq 0.3$	–	mA	
MultiCAN ERU LEDTSCU0 CCU4x CCU8x		–	$\leq 1.0$	–		
DAC (digital) <sup>1)</sup>		–	1.3	–		
USICx		–	3.0	–		
DSD VADC (digital) <sup>1)</sup>		–	4.5	–		
DMAx		–	6.0	–		

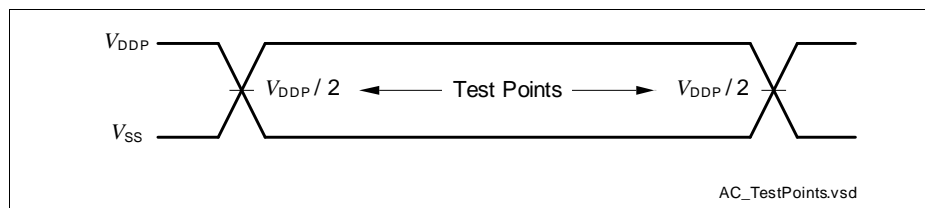
1) The current consumption of the analog components are given in the dedicated Data Sheet sections of the respective peripheral.

### 3.3 AC Parameters

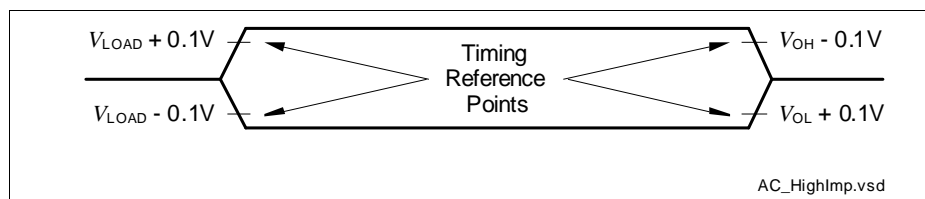
#### 3.3.1 Testing Waveforms



**Figure 23 Rise/Fall Time Parameters**



**Figure 24 Testing Waveform, Output Delay**



**Figure 25 Testing Waveform, Output High Impedance**

### 3.3.4 Phase Locked Loop (PLL) Characteristics

#### Main and USB PLL

**Table 44 PLL Parameters**

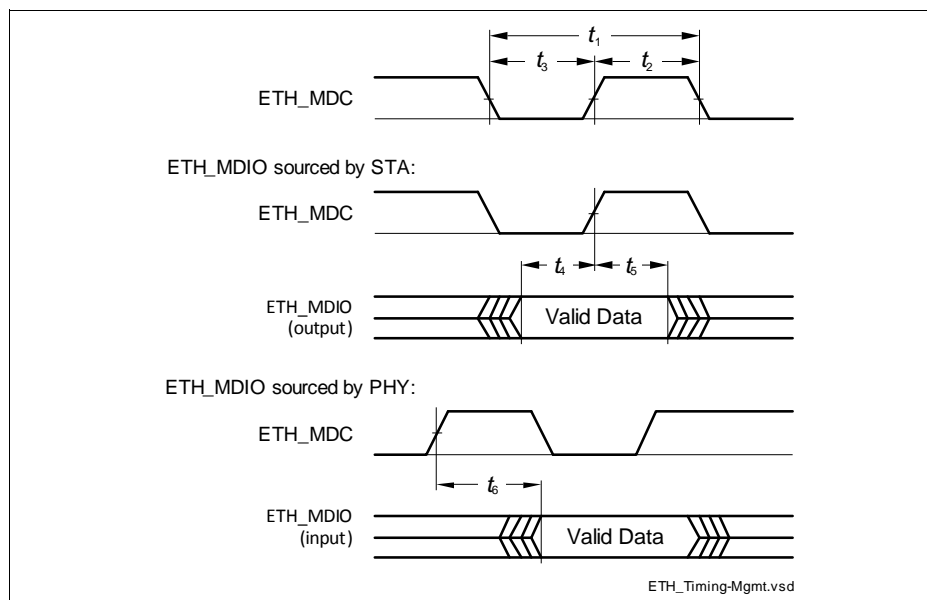
Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Accumulated Jitter	$D_P$ CC	–	–	±5	ns	accumulated over 300 cycles $f_{SYS} = 120$ MHz
Duty Cycle <sup>1)</sup>	$D_{DC}$ CC	46	50	54	%	Low pulse to total period, assuming an ideal input clock source
PLL base frequency	$f_{PLLBASE}$ CC	30	–	140	MHz	
VCO input frequency	$f_{REF}$ CC	4	–	16	MHz	
VCO frequency range	$f_{VCO}$ CC	260	–	520	MHz	
PLL lock-in time	$t_L$ CC	–	–	400	µs	

1) 50% for even K2 divider values, 50±(10/K2) for odd K2 divider values.

### 3.3.11.2 ETH Management Signal Parameters (ETH\_MDC, ETH\_MDIO)

**Table 58 ETH Management Signal Timing Parameters**

Parameter	Symbol		Values			Unit	Note / Test Condi on
			Min.	Typ.	Max.		
ETH_MDC period	$t_1$	CC	400	—	—	ns	$C_L = 25 \text{ pF}$
ETH_MDC high time	$t_2$	CC	160	—	—	ns	
ETH_MDC low time	$t_3$	CC	160	—	—	ns	
ETH_MDIO setup time (output)	$t_4$	CC	10	—	—	ns	
ETH_MDIO hold time (output)	$t_5$	CC	10	—	—	ns	
ETH_MDIO data valid (input)	$t_6$	SR	0	—	300	ns	



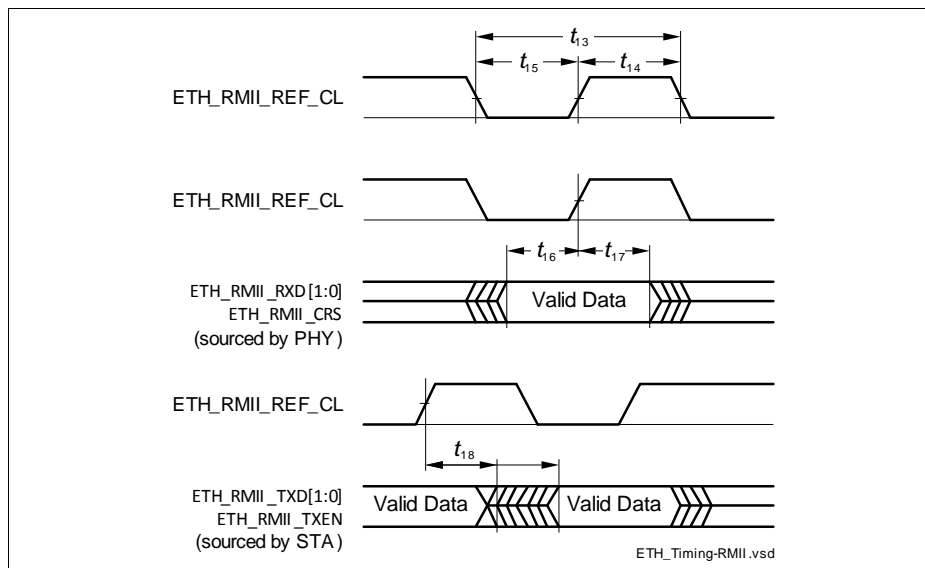
**Figure 40 ETH Management Signal Timing**

### 3.3.11.3 ETH RMII Parameters

In the following, the parameters of the RMII (Reduced Media Independent Interface) are described.

**Table 59 ETH RMII Signal Timing Parameters**

Parameter	Symbol		Values			Unit	Note / Test Condition
			Min.	Typ.	Max.		
ETH_RMII_REF_CL clock period	$t_{13}$	SR	20	–	–	ns	$C_L = 25 \text{ pF}$ ; 50 ppm
ETH_RMII_REF_CL clock high time	$t_{14}$	SR	7	–	13	ns	$C_L = 25 \text{ pF}$
ETH_RMII_REF_CL clock low time	$t_{15}$	SR	7	–	13	ns	
ETH_RMII_RXD[1:0], ETH_RMII_CRD setup time	$t_{16}$	SR	4	–	–	ns	
ETH_RMII_RXD[1:0], ETH_RMII_CRD hold time	$t_{17}$	SR	2	–	–	ns	
ETH_RMII_TXD[1:0], ETH_RMII_TXEN data valid	$t_{18}$	CC	4	–	15	ns	



**Figure 41 ETH RMII Signal Timing**

## Package and Reliability

The maximum heat that can be dissipated depends on the package and its integration into the target board. The “Thermal resistance  $R_{\Theta JA}$ ” quantifies these parameters. The power dissipation must be limited so that the average junction temperature does not exceed 150 °C.

The difference between junction temperature and ambient temperature is determined by  $\Delta T = (P_{INT} + P_{IOSTAT} + P_{IODYN}) \times R_{\Theta JA}$

The internal power consumption is defined as

$$P_{INT} = V_{DDP} \times I_{DDP} \text{ (switching current and leakage current).}$$

The static external power consumption caused by the output drivers is defined as

$$P_{IOSTAT} = \Sigma((V_{DDP} - V_{OH}) \times I_{OH}) + \Sigma(V_{OL} \times I_{OL})$$

The dynamic external power consumption caused by the output drivers ( $P_{IODYN}$ ) depends on the capacitive load connected to the respective pins and their switching frequencies.

If the total power dissipation for a given system configuration exceeds the defined limit, countermeasures must be taken to ensure proper system operation:

- Reduce  $V_{DDP}$ , if possible in the system
- Reduce the system frequency
- Reduce the number of output pins
- Reduce the load on active output drivers

## 4.2 Package Outlines

The availability of different packages for different devices types is listed in [Table 1](#), specific packages for different device markings are listed in [Table 2](#).

The exposed die pad dimensions are listed in [Table 60](#).

**Table 61 Differences PG-LQFP-100-11 to PG-LQFP-100-24**

Change	PG-LQFP-100-11	PG-LQFP-100-25
Thermal Resistance Junction Ambient ( $R_{\Theta JA}$ )	20.5 K/W	20.0 K/W
Lead Width	0.22 <sup>+0.05</sup> mm	0.2 <sup>+0.07</sup> <sub>-0.03</sub> mm
Lead Thickness	0.15 <sup>+0.05</sup> <sub>-0.06</sub> mm	0.127 <sup>+0.073</sup> <sub>-0.037</sub> mm
Exposed Die Pad outer dimensions	7.0 mm × 7.0 mm	7.0 mm × 7.0 mm
Exposed Die Pad U-Groove inner dimensions	n.a.	6.2 mm × 6.2 mm